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| Notice of References Cited | Application/Control No. 10/530,084 | | Applicant(s)/Patent Under Reexamination HAENEN ET AL. | |
| | Examiner SATHAVARAM I. REDDY | | Art Unit 1794 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-4,460,637 | 07-1984 | Miyamoto et al. | 428/32.32 |
| * | B | US-5,437,913 | 08-1995 | Asaka et al. | 428/195.1 |
| * | C | US-5,418,078 | 05-1995 | Desie et al. | 428/32.3 |
| * | D | US-4,408,010 | 10-1983 | Le-Khac, Bi | 525/73 |
| * | E | US-5,418,110 | 05-1995 | Uytterhoeven et al. | 430/200 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|-----------|----------------|
| | N | EP 0 0803 374 | 10-1997 | Japan | Liu et al | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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